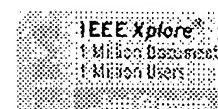


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1 Calculating the optical properties of multidimensional heterostructures: Application to the modeling of quaternary quantum well lasers

Gershoni, D.; Henry, C.H.; Baraff, G.A.;

Quantum Electronics, IEEE Journal of , Volume: 29 , Issue: 9 , Sept. 1993
Pages:2433 - 2450[\[Abstract\]](#) [\[PDF Full-Text \(1484 KB\)\]](#) **IEEE JNL****2 Effect of GaNAs strain compensating layer over InAs quantum dots grown by MOMBE**

Ganapathy, S.; Zhang, X.Q.; Uesugi, K.; Kumano, H.; Suemune, I.; Kim, B.J.; Seong, T.Y.;

Indium Phosphide and Related Materials Conference, 2002. IPRM. 14th , 12-16 May 2002
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